



GM71C16160C GM71CS16160CL

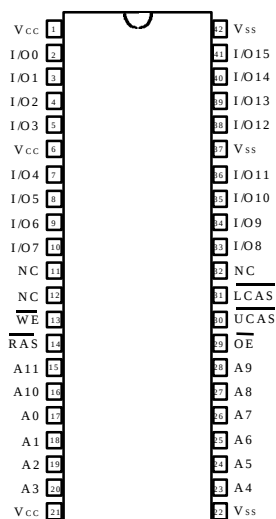
1,048,576 WORDS x 16 BIT
CMOS DYNAMIC RAM

Description

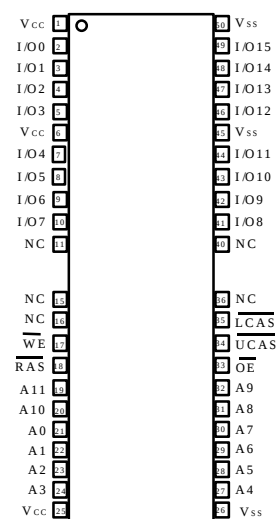
The GM71C(S)16160C/CL is the new generation dynamic RAM organized 1,048,576 x 16 bit. GM71C(S)16160C/CL has realized higher density, higher performance and various functions by utilizing advanced CMOS process technology. The GM71C(S)16160C/CL offers Fast Page Mode as a high speed access mode. Multiplexed address inputs permit the GM71C(S)16160C/CL to be packaged in standard 400 mil 42 pin plastic SOJ, and standard 400mil 44(50)pin plastic TSOP II. The package size provides high system bit densities and is compatible with widely available automated testing and insertion equipment.

Pin Configuration

42 SOJ



44(50) TSOP II



(Top View)

Features

- * 1,048,576 Words x 16 Bit Organization
- * Fast Page Mode Capability
- * Single Power Supply (5V+/-10%)
- * Fast Access Time & Cycle Time (Unit: ns)

	t _{RAC}	t _{CAC}	t _{RC}	t _{PC}
GM71C(S)16160C/CL-5	50	13	90	35
GM71C(S)16160C/CL-6	60	15	110	40
GM71C(S)16160C/CL-7	70	18	130	45

- * Low Power
 - Active : 605/550/495mW (MAX)
 - Standby : 11mW (CMOS level : MAX)
 - 0.83mW (L-version : MAX)
- * RAS Only Refresh, CAS before RAS Refresh, Hidden Refresh Capability
- * All inputs and outputs TTL Compatible
- * 4096 Refresh Cycles/64ms
- * 4096 Refresh Cycles/128ms (L-version)
- * Self Refresh Operation (L-version)
- * Battery Back Up Operation (L-version)
- * 2 CAS byte Control



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Pin Description

Pin	Function	Pin	Function
	Address Inputs	$\overline{\text{WE}}$	Read / Write Enable
	Refresh Address Inputs	$\overline{\text{OE}}$	Output Enable
	Data Input / Data Output	V_{CC}	Power (+5V)
$\overline{\text{RAS}}$	Row Address Strobe	V_{SS}	Ground
$\overline{\text{UCAS}}, \overline{\text{LCAS}}$	Column Address Strobe	NC	No Connection

Ordering Information

Type No.	Access Time	Package
GM71C(S)16160CJ/CLJ -5 GM71C(S)16160CJ/CLJ -6 GM71C(S)16160CJ/CLJ -7	50ns 60ns 70ns	400 Mil 42 Pin Plastic SOJ
GM71C(S)16160CT/CLT -5 GM71C(S)16160CT/CLT -6 GM71C(S)16160CT/CLT -7	50ns 60ns 70ns	400 Mil 44(50) Pin Plastic TSOP II

Absolute Maximum Ratings*

Symbol	Parameter	Rating	Unit
T_{A}	Ambient Temperature under Bias	0 ~ +70	C
T_{STG}	Storage Temperature (Plastic)	-55 ~ +125	C
$V_{\text{IN/OUT}}$	Voltage on any Pin Relative to V_{SS}	-1.0 ~ +7.0V	V
V_{CC}	Voltage on V_{CC} Relative to V_{SS}	-1.0 ~ +7.0V	V
I_{OUT}	Short Circuit Output Current	50	mA
P_{D}	Power Dissipation	1.0	W

Note: Operation at or above Absolute Maximum Ratings can adversely affect device reliability.

Recommended DC Operating Conditions ($T_A = 0 \sim +70^\circ\text{C}$)

Symbol	Parameter	Min	Typ	Max	Unit
V_{CC}	Supply Voltage	4.5	5.0	5.5	V
V_{IH}	Input High Voltage	2.4	-	6.0	V
V_{IL}	Input Low Voltage	-1.0	-	0.8	V

Note: All voltage referred to V_{SS} .

The supply voltage with all VCC pins must be on the same level. The supply voltage with all VSS pins must be on the same level.

Truth Table

$\overline{RAS}$	$\overline{LCAS}$	$\overline{UCAS}$	$\overline{WE}$	$\overline{OE}$	Output	Operation		Notes
H	D	D	D	D	Open	Standby		1,3
L	L	H	H	L	Valid	Lower byte	Read cycle	1,3
L	H	L	H	L	Valid	Upper byte		
L	L	L	H	L	Valid	Word		
L	L	H	L	D	Open	Lower byte	Early write cycle	1,2,3
L	H	L	L	D	Open	Upper byte		
L	L	L	L	D	Open	Word		
L	L	H	L	H	Undefined	Lower byte	Delayed Write cycle	1,2,3
L	H	L	L	H	Undefined	Upper byte		
L	L	L	L	H	Undefined	Word		
L	L	H	H to L	L to H	Valid	Lower byte	Read-modify-write cycle	1,3
L	H	L	H to L	L to H	Valid	Upper byte		
L	L	L	H to L	L to H	Valid	Word		
H to L	H	L	D	D	Open	Word	CBR Refresh or Self Refresh (L-series)	1,3
H to L	L	H	D	D	Open	Word		
H to L	L	L	D	D	Open	Word		
L	H	H	D	D	Open	Word	RAS-only Refresh cycle	1,3
L	L	L	H	H	Open	Read cycle (Output disabled)		1,3

Notes: 1. H: High (inactive) L: Low(active) D: H or L

2. $t_{wcs} \geq 0\text{ns}$ Early write cycle

$t_{wcs} \leq 0\text{ns}$ Delayed write cycle

3. Mode is determined by the OR function of the $\overline{UCAS}$ and $\overline{LCAS}$. (Mode is set by earliest of $\overline{UCAS}$ and $\overline{LCAS}$ active edge and reset by the latest of $\overline{UCAS}$ and $\overline{LCAS}$ inactive edge.) However write OPERATION and output High-Z control are done independently by each $\overline{UCAS}$, $\overline{LCAS}$.
 ex) if $RAS = H$ to L, $UCAS = H$, $LCAS = L$, then CAS-before-RAS refresh cycle is selected.

$V_{CC} = 5V \pm 10\%, V_{SS}$
 $A = 0 \sim 70^\circ C$

Symbol	Parameter	Min	Max	Unit	Note
V_{OH}	Output Level Output "H" Level Voltage ($I_{OUT} = -5mA$)	2.4	V_{CC}	V	
V_{OL}	Output Level Output "L" Level Voltage ($I_{OUT} = 4.2mA$)	0	0.4	V	
I_{CC1}	Operating Current (RAS, UCAS or LCAS Cycling: $t_{RC} = t_{RC \min}$)	50ns	110	mA	1, 2
		ns	100		
		70	90		
I_{CC2}	Standby Current (TTL) Power Supply Standby Current (RAS, UCAS, LCAS = V_{IH} , $D_{OUT} = \text{High-Z}$)	-	2	mA	
I_{CC3}	RAS Only Refresh Current Average Power Supply Current RAS Only Refresh Mode ($t_{RC} = t_{RC \min}$)	50ns	110		2
		ns	100		
		70	90		
I_{CC4}	Fast Page Mode Current Fast Page Mode ($t_{PC} = t_{PC \min}$)	50ns	115	mA	
		ns	105		
		70	95		
I_{CC5}	Standby Current (CMOS) Power Supply Standby Current (RAS, UCAS or LCAS $\geq V_{CC} - 0.2V$, $D_{OUT} = \text{High-Z}$)	-	1	mA	
		-	150		5
I_{CC6}	CAS-before-RAS Refresh Current ($t_{RC} = t_{RC \min}$)	50ns	110	mA	
		ns	-		
		70	90		
	(Standby with CBR Refresh) ($t_{RC} = 31.3\mu s$, $t_{RC} \leq 0.3$, $D_{OUT} =$	-	500	μA	
I_{CC8}	 UCAS, LCAS = V D_{OUT}	-		mA	1
I_{CC9}	 (RAS, UCAS or LCAS $\leq 0.2V$, $D_{OUT} =$	-	300	μA	
$I_{L(I)}$	Input Leakage Current Any Input ($0V \leq V_{IN} \leq 6V$)	-10	10	μA	
$I_{L(O)}$	Output Leakage Current (D_{OUT} is Disabled, $0V \leq V_{OUT} \leq 6V$)	-10	10	μA	

Note: 1. I_{CC} depends on output load condition when the device is selected.

(max) is specified at the output open condition.

2. Address can be changed once or less while $RAS = V_{IL}$.

3. Address can be changed once or less while LCAS and UCAS = V_{IH} .

5. L-version.



GM71C16160C GM71CS16160CL

Capacitance ($V_{CC} = 5V \pm 10\%$, $T_A = 25^\circ C$)

Symbol	Parameter	Min	Max	Unit	Note
C_{I1}	Input Capacitance (Address)	-	5	pF	1
C_{I2}	Input Capacitance (Clocks)	-	7	pF	1
$C_{I/O}$	Output Capacitance (Data-In /Out)	-	7	pF	1, 2

Note: 1. Capacitance measured with Boonton Meter or effective capacitance measuring method.

2. UCAS and LCAS = V_{IH} to disable D_{OUT} .

AC Characteristics ($V_{CC} = 5V \pm 10\%$, $T_A = 0 \sim +70^\circ C$, $V_{SS} = 0V$, Note 1, 2, 3, 19)

Test Conditions

Input rise and fall times : 5 ns

Output timing reference levels : 0.4V, 2.4V

Input timing reference levels : 0.8V, 2.4V

Output load : 2TTL gate + C_L (100 pF)

(Including scope and jig)

Read, Write, Read-Modify-Write and Refresh Cycles (Common Parameters)

Symbol	Parameter	GM71C(S)16160 C/CL-5		GM71C(S)16160 C/CL-6		GM71C(S)16160 C/CL-7		Unit	Note
		Min	Max	Min	Max	Min	Max		
t_{RC}	Random Read or Write Cycle Time	90	-	110	-	130	-	ns	
t_{RP}	RAS Precharge Time	30	-	40	-	50	-	ns	
t_{CP}	CAS Precharge Time	7	-	10	-	10	-	ns	25
t_{RAS}	RAS Pulse Width	50	10,000	60	10,000	70	10,000	ns	
t_{CAS}	CAS Pulse Width	13	10,000	15	10,000	18	10,000	ns	
t_{ASR}	Row Address Set up Time	0	-	0	-	0	-	ns	
t_{RAH}	Row Address Hold Time	7	-	10	-	10	-	ns	
t_{ASC}	Column Address Set-up Time	0	-	0	-	0	-	ns	22
t_{CAH}	Column Address Hold Time	7	-	10	-	15	-	ns	22
t_{RCD}	RAS to CAS Delay Time	17	45	20	45	20	52	ns	4
t_{RAD}	RAS to Column Address Delay Time	12	30	15	30	15	35	ns	5
t_{RSH}	RAS Hold Time	13	-	15	-	18	-	ns	
t_{CSH}	CAS Hold Time	50	-	60	-	70	-	ns	
t_{CRP}	CAS to RAS Precharge Time	5	-	5	-	5	-	ns	23
t_{ODD}	OE to D_{IN} Delay Time	13	-	15	-	18	-	ns	6
t_{DZO}	OE Delay Time from D_{IN}	0	-	0	-	0	-	ns	7
t_{DZC}	CAS Delay Time from D_{IN}	0	-	0	-	0	-	ns	7
t_T	Transition Time (Rise and Fall)	3	50	3	50	3	50	ns	8

Read Cycle

Symbol	Parameter	GM71C(S)16160 C/CL-5		GM71C(S)16160 C/CL-6		GM71C(S)16160 C/CL-7		Unit	Note
		Min	Max	Min	Max	Min	Max		
t_{RAC}	Access Time from $\overline{RAS}$	-	50	-	60	-	70	ns	9,10
t_{CAC}	Access Time from $\overline{CAS}$	-	13	-	15	-	18	ns	10,11,18
t_{AA}	Access Time from Address	-	25	-	30	-	35	ns	10,11,18
t_{OAC}	Access Time from $\overline{OE}$	-	13	-	15	-	18	ns	10,26
t_{RCS}	Read Command Setup Time	0	-	0	-	0	-	ns	
t_{RCH}	Read Command Hold Time to $\overline{CAS}$	0	-	0	-	0	-	ns	13,23
t_{RRH}	Read Command Hold Time to $\overline{RAS}$	5	-	5	-	5	-	ns	13
t_{RAL}	Column Address to $\overline{RAS}$ Lead Time	25	-	30	-	35	-	ns	
t_{CAL}	Column Address to $\overline{CAS}$ Lead Time	25	-	30	-	35	-	ns	
t_{CLZ}	$\overline{CAS}$ to Output in Low-Z	0	-	0	-	0	-	ns	
t_{OH}	Output Data Hold Time	3	-	3	-	3	-	ns	
t_{OHO}	Output Data Hold Time from $\overline{OE}$	3	-	3	-	3	-	ns	
t_{OFF}	Output Buffer Turn-off Time	-	13	-	15	-	15	ns	14
t_{OEZ}	Output Buffer Turn-off Time to $\overline{OE}$	-	13	-	15	-	15	ns	14
t_{CDD}	$\overline{CAS}$ to D_{IN} Delay Time	13	-	15	-	18	-	ns	6

Write Cycle

Symbol	Parameter	GM71C(S)16160 C/CL-5		GM71C(S)16160 C/CL-6		GM71C(S)16160 C/CL-7		Unit	Note
		Min	Max	Min	Max	Min	Max		
t_{WCS}	Write Command Setup Time	0	-	0	-	0	-	ns	15,22
t_{WCH}	Write Command Hold Time	7	-	10	-	15	-	ns	22
t_{Wp}	Write Command Pulse Width	7	-	10	-	10	-	ns	
t_{RWL}	Write Command to $\overline{RAS}$ Lead Time	13	-	15	-	18	-	ns	
t_{CWL}	Write Command to $\overline{CAS}$ Lead Time	13	-	15	-	18	-	ns	24
t_{DS}	Data-in Setup Time	0	-	0	-	0	-	ns	16,24
t_{DH}	Data-in Hold Time	7	-	10	-	15	-	ns	16,24

Read- Modify-Write Cycle

Symbol	Parameter	GM71C(S)16160 C/CL-5		GM71C(S)16160 C/CL-6		GM71C(S)16160 C/CL-7		Unit	Note
		Min	Max	Min	Max	Min	Max		
t_{RWC}	Read-Modify-Write Cycle Time	131	-	155	-	181	-	ns	
t_{RWD}	$\overline{RAS}$ to $\overline{WE}$ Delay Time	73	-	85	-	98	-	ns	15
t_{CWD}	CAS to $\overline{WE}$ Delay Time	36	-	40	-	46	-	ns	15
t_{AWD}	Column Address to $\overline{WE}$ Delay Time	48	-	55	-	63	-	ns	15
t_{OEh}	OE Hold Time from $\overline{WE}$	13	-	15	-	18	-	ns	

Refresh Cycle

Symbol	Parameter	GM71C(S)16160 C/CL-5		GM71C(S)16160 C/CL-6		GM71C(S)16160 C/CL-7		Unit	Note
		Min	Max	Min	Max	Min	Max		
t_{CSR}	$\overline{CAS}$ Setup Time (CAS-before-RAS Refresh Cycle)	5	-	5	-	5	-	ns	22
t_{CHR}	$\overline{CAS}$ Hold Time (CAS-before-RAS Refresh Cycle)	7	-	10	-	10	-	ns	23
t_{RPC}	$\overline{RAS}$ Precharge to $\overline{CAS}$ Hold Time	5	-	5	-	5	-	ns	22

Fast Page Mode Cycle

Symbol	Parameter	GM71C(S)16160 C/CL-5		GM71C(S)16160 C/CL-6		GM71C(S)16160 C/CL-7		Unit	Note
		Min	Max	Min	Max	Min	Max		
t_{PC}	Fast Page Mode Cycle Time	35	-	40	-	45	-	ns	
t_{RASP}	Fast Page Mode $\overline{RAS}$ Pulse Width	-	100,000	-	100,000	-	100,000	ns	17
t_{ACP}	Access Time from $\overline{CAS}$ Precharge	-	30	-	35	-	40	ns	10,18,23
t_{RHCP}	$\overline{RAS}$ Hold Time from $\overline{CAS}$ Precharge	30	-	35	-	40	-	ns	

Fast Page Mode Read-Modify-Write Cycle

Symbol	Parameter	GM71C(S)16160 C/CL-5		GM71C(S)16160 C/CL-6		GM71C(S)16160 C/CL-7		Unit	Note
		Min	Max	Min	Max	Min	Max		
t_{PRWC}	Fast Page Mode Read-Modify-Write Cycle Time	76	-	85	-	96	-	ns	
t_{CPW}	$\overline{WE}$ Delay Time from CAS Precharge	53	-	60	-	68	-	ns	15,23

Self Refresh

Mode Symbol	Parameter	GM71CS16160 CL-5		GM71CS16160 CL-6		GM71CS16160 CL-7		Unit	Note
		Min	Max	Min	Max	Min	Max		
t_{RASS}	$\overline{RAS}$ Pulse Width(Self-Refresh)	100	-	100	-	100	-	us	27
t_{RPS}	$\overline{RAS}$ Precharge Time(Self-Refresh)	90	-	110	-	130	-	ns	
t_{CHS}	$\overline{CAS}$ Hold Time(Self-Refresh)	-50	-	-50	-	-50	-	ns	

Notes:

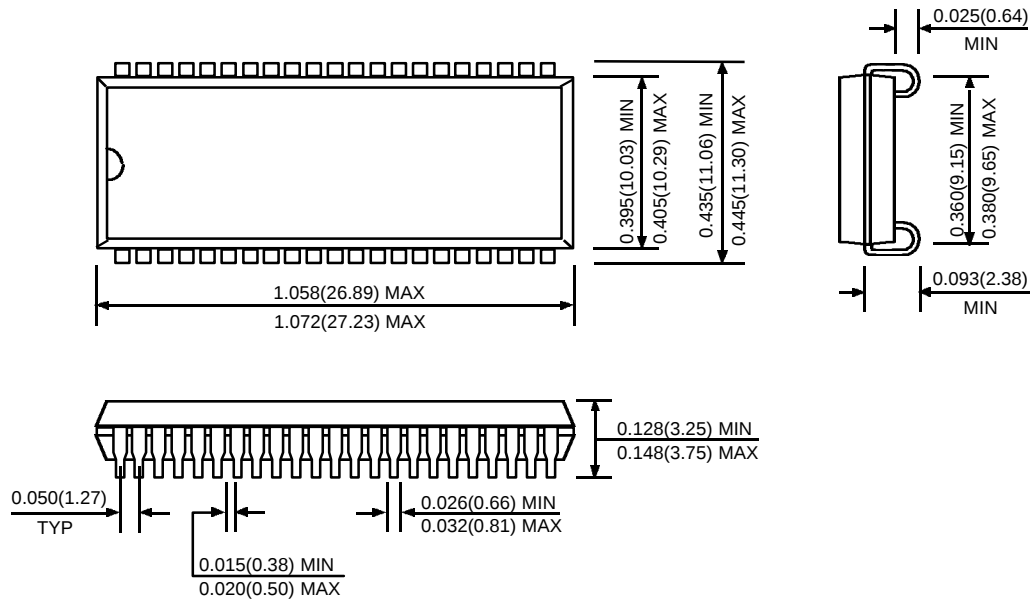
1. AC measurements assume $t_r = 5ns$.
2. An initial pause of 200us is required after power up followed by a minimum of eight initialization cycles(any combination of cycles containing RAS-only refresh or CAS-before-RAS refresh). If the internal refresh counter is used, a minimum of eight CAS-before-RAS refresh cycles are required.
3. Only row address is indispensable on address A8, A9, A10, A11.
4. Operation with the $t_{RCD}(max)$ limit insures that $t_{RAC}(max)$ can be met, $t_{RCD}(max)$ is specified as a reference point only; if $t_{RCD} \geq t_{RAD}(max) + t_{AA}(max) - t_{CAC}(max)$, then access time is controlled exclusively by t_{CAC} .
5. Operation with the $t_{RAD}(max)$ limit insures that $t_{RAC}(max)$ can be met, $t_{RAD}(max)$ is specified as a reference point only; if t_{RAD} is greater than the specified $t_{RAD}(max)$ limit, then access time is controlled exclusively by t_{AA} .
6. Either t_{ODD} or t_{CDD} must be satisfied.
7. Either t_{DZO} or t_{DZC} must be satisfied.
8. $V_{IH}(min)$ and $V_{IL}(max)$ are reference levels for measuring timing of input signals. Also, transition times are measured between $V_{IH}(min)$ and $V_{IL}(max)$.
9. Assumes that $t_{RCD} \leq t_{RCD}(max)$ and $t_{RAD} \leq t_{RAD}(max)$. If t_{RCD} or t_{RAD} is greater than the maximum recommended value shown in this table, t_{RAC} exceeds the value shown.
10. Measured with a load circuit equivalent to 2 TTL load and 100pF.
11. Assumes that $t_{RCD} \geq t_{RCD}(max)$ and $t_{RCD} + t_{CAC}(max) \geq t_{RAD} + t_{AA}(max)$.
12. Assumes that $t_{RAD} \geq t_{RAD}(max)$ and $t_{RCD} + t_{CAC}(max) \leq t_{RAD} + t_{AA}(max)$.

Either t_{RCH} or t_{RRH} must be satisfied for a read cycles.

14. $t_{OFF(max)}$ and $t_{OEZ(max)}$ define the time at which the outputs achieve the open circuit condition and are not referred to output voltage levels.
 t_{WCS} , t_{CPW} , t_{AWD} are not restrictive operating parameters. They are included in the data sheet as electrical characteristics only; if $t_{WCS} \geq t_{WCS(min)}$, the cycle is an early write cycle and the data out pin will remain open circuit (high impedance) throughout the entire cycle; if $t_{RWD} \geq t_{RWD(min)}$, $t_{CWD} \geq t_{CWD(min)}$, or $t_{AWD} \geq t_{AWD(min)}$, the data out pin will contain data read from the selected cell; if neither of the above sets of conditions is satisfied, the condition of data out (at access time) is indeterminate.
- WE leading edge in delayed write or read-modify-write cycles.
17. t_{RASP}
18. Access time is determined by the longest among t_{AA} , t_{ACP} , and t_{ACP} .
19. In delayed write or read-modify-write cycles, OE must disable output buffer prior to applying data to the device. After RAS is reset, if $t_{OE} \geq t_{CWL}$, the I/O pin will remain open circuit (high impedance); if $t_{OE} < t_{CWL}$, invalid data will be out at each I/O.
20. When both UCAS and LCAS go low at the same time, all 16-bit data are written into the device. UCAS and LCAS cannot be staggered within the same write/read cycles.
21. All the V_{CC} and V_{SS} pins shall be supplied with the same voltages.
22. t_{ASC} , t_{CAH} , t_{RCS} , t_{WCS} , t_{WCH} , t_{CSR} and t_{RPC} are determined by the earlier falling edge of UCAS or LCAS.
23. t_{CRP} , t_{CHR} , t_{RCH} , t_{ACP} and t_{CPW} are determined by the later rising edge of UCAS or LCAS.
24. t_{CWL} , t_{DH} , t_{DS} and t_{CSH} should be satisfied by both UCAS and LCAS.
25. t_{CP} is determined by that time the both UCAS and LCAS are high.
26. When output buffers are enabled once, sustain the low impedance state until valid data is obtained.
 When output buffer is turned on and off within a very short time, generally it causes large V_{CC}/V_{SS} line noise, which causes to degrade $V_{IH(min)}/V_{IL(max)}$ level.
27. Please do not use t_{RASS} timing, $10\mu s \leq t_{RASS}$
 transition state from normal operation mode to self refresh mode. If $t_{RASS} \geq 100\mu s$, then RAS precharge time should use t_{RPS} instead of t_{RP} .
28. If you use distributed CBR refresh within 15.6us interval in normal read/write cycle, CBR refresh should be executed within 15.6us immediately after exiting from and before entering into self refresh mode.
29. If you use RAS only refresh or CBR burst refresh mode in normal read/write cycle, 4096 or 1024 cycles of distributed CBR refresh with 15.6us interval should be executed within 64 or 16ms immediately after exiting from and before entering into the self refresh mode.
30. Repetitive self refresh mode without refreshing all memory is not allowed. Once you exit from self refresh mode, all memory cells need to be refreshed before re-entering the self refresh mode again.
31. H or L ($V_{IH(min)} \leq V_{IH} \leq V_{IL(max)}$)

Package Dimension

Unit: Inches (mm)

42 SOJ

44(50) TSOP I
